捷多邦,专业PCB打样工厂,24小时加急出货

ZX3CDBS1M832

MPPS[™] Miniature Package Power Solutions 20V NPN LOW SATURATION TRANSISTOR AND 40V, 1A SCHOTTKY **DIODE COMBINATION DUAL**

SUMMARY

NPN Transistor — V_{CEO} = 20V; R_{SAT} = 47m Ω ; I_C = 4.5A

Schottky Diode — $V_R = 40V$; $V_F = 500mV$ (@1A); $I_C = 1A$

DESCRIPTION

Packaged in the new innovative 3mm x 2mm MLP this combination dual comprises an ultra low saturation PNP transistor and a 1A Schottky barrier diode. This excellent combination provides users with highly efficient performance in applications including DC-DC and charging circuits.

Users will also gain several other key benefits:

Performance capability equivalent to much larger packages

Improved circuit efficiency & power levels

PCB area and device placement savings

Lower package height (0.9mm nom)

Reduced component count

FEATURES

- Extremely Low Saturation Voltage (150mV @1A)
- H_{FE} characterised up to 6A
- I_C = 4.5A Continuous Collector Current
- Extremely Low V_F, fast switching Schottky
- 3mm x 2mm MLP

APPLICATIONS

- DC DC Converters
- **Mobile Phones**
- Charging Circuits
- Motor control

ORDERING INFORMATION

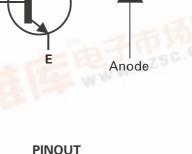
DEVICE	REEL	TAPE WIDTH	QUANTITY PER REEL
ZX3CDBS1M832TA	7''	8mm	3000
ZX3CDBS1M832TC	13''	8mm	10000
	EQ.	W.OZ!	50.00

DEVICE MARKING

BS1

ISSUE 1 - JUNE 2002



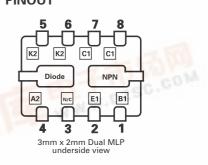


С

B

3mm x 2mm Dual Die MLP

Cathode





ABSOLUTE MAXIMUM RATINGS.

PARAMETER	SYMBOL	VALUE	UNIT
Transistor			
Collector-Base Voltage	V _{CBO}	40	V
Collector-Emitter Voltage	V _{CEO}	20	V
Emitter-Base Voltage	V _{EBO}	7.5	V
Peak Pulse Current	I _{CM}	12	А
Continuous Collector Current (a)(f)	Ι _C	4.5	А
Continuous Collector Current (b)(f)	Ι _C	5	А
Base Current	IB	1000	mA
Power Dissipation at TA=25°C (a)(f) Linear Derating Factor	P _D	1.5 12	W mW/°C
Power Dissipation at TA=25°C (b)(f) Linear Derating Factor	P _D	2.45 19.6	W mW/°C
Power Dissipation at TA=25°C (c)(f) Linear Derating Factor	P _D	1 8	W mW/°C
Power Dissipation at TA=25°C (d)(f) Linear Derating Factor	P _D	1.13 9	W mW/°C
Power Dissipation at TA=25°C (d)(g) Linear Derating Factor	P _D	1.7 13.6	W mW/°C
Power Dissipation at TA=25°C (e)(g) Linear Derating Factor	P _D	3 24	W mW/°C
Storage Temperature Range	T _{stg}	-55 to +150	°C
Junction Temperature	Ti	150	°C

THERMAL RESISTANCE

PARAMETER	SYMBOL	VALUE	UNIT
Junction to Ambient (a)(f)	R _{θJA}	83	°C/W
Junction to Ambient (b)(f)	R _{θJA}	51	°C/W
Junction to Ambient (c)(f)	$R_{\theta JA}$	125	°C/W
Junction to Ambient (d)(f)	R _{0JA}	111	°C/W
Junction to Ambient (d)(g)	R _{0JA}	73.5	°C/W
Junction to Ambient (e)(g)	R _{0JA}	41.7	°C/W

Notes

(a) For a dual device surface mounted on 8 sq cm single sided 2oz copper on FR4 PCB, in still air conditions with all exposed pads attached. The copper area is split down the centre line into two separate areas with one half connected to each half of the dual device.

(b) Measured at t<5 secs for a dual device surface mounted on 8 sq cm single sided 2oz copper on FR4 PCB, in still air conditions with all exposed pads attached. The copper area is split down the centre line into two separate areas with one half connected to each half of the dual device.

(c) For a dual device surface mounted on 8 sq cm single sided 2oz copper on FR4 PCB, in still air conditions with minimal lead connections only.
(d) For a dual device surface mounted on 10 sq cm single sided 1oz copper on FR4 PCB, in still air conditions with all exposed pads attached attached. The copper area is split down the centre line into two separate areas with one half connected to each half of the dual device.
(e) For a dual device surface mounted on 85 sq cm single sided 2oz copper on FR4 PCB, in still air conditions with all exposed pads attached.

(e) For a dual device surface mounted on 85 sq cm single sided 2oz copper on FR4 PCB, in still air conditions with all exposed pads attached attached. The copper area is split down the centre line into two separate areas with one half connected to each half of the dual device. (f) For a dual device with one active die.

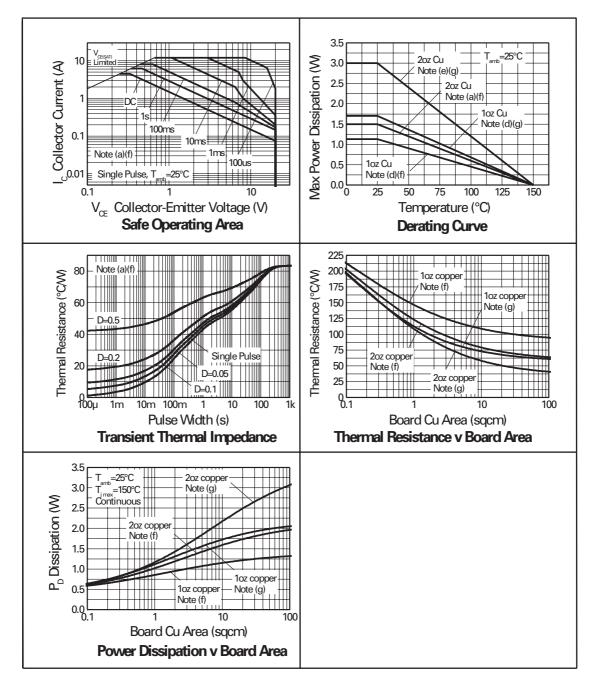
(g) For dual device with 2 active die running at equal power.

(h) Repetitive rating - pulse width limited by max junction temperature. Refer to Transient Thermal Impedance graph.

(i) The minimum copper dimensions required for mounting are no smaller than the exposed metal pads on the base of the device as shown in the package dimensions data. The thermal resistance for a dual device mounted on 1.5mm thick FR4 board using minimum copper 1 oz weight, 1mm wide tracks and one half of the device active is Rth = 250°C/W giving a power rating of Ptot = 500mW.









ABSOLUTE MAXIMUM RATINGS.

PARAMETER	SYMBOL	VALUE	UNIT
Schottky Diode	L.		
Continuous Reverse Voltage	V _R	40	V
Forward Voltage @ I _F =1000mA(typ)	V _F	425	А
Forward Current	I _F	1850	mA
Average Peak Forward Current D=50%	I _{FAV}	3	А
Non Repetitive Forward Current t≤ 100µs t≤ 10ms	I _{FSM}	12 7	A A
Power Dissipation at TA=25°C (a)(f) Linear Derating Factor	P _D	1.2 12	W mW/°C
Power Dissipation at TA=25°C (b)(f) Linear Derating Factor	P _D	2 20	W mW/°C
Power Dissipation at TA=25°C (c)(f) Linear Derating Factor	P _D	0.8 8	W mW/°C
Power Dissipation at TA=25°C (d)(f) Linear Derating Factor	P _D	0.9 9	W mW/°C
Power Dissipation at TA=25°C (d)(g) Linear Derating Factor	P _D	1.36 13.6	W mW/°C
Power Dissipation at TA=25°C (e)(g) Linear Derating Factor	P _D	2.4 24	W mW/°C
Storage Temperature Range	T _{stg}	-55 to +150	°C
Junction Temperature	Ti	125	°C

THERMAL RESISTANCE

PARAMETER	SYMBOL	VALUE	UNIT
Junction to Ambient (a)(f)	R _{0JA}	83	°C/W
Junction to Ambient (b)(f)	R _{0JA}	51	°C/W
Junction to Ambient (c)(f)	R _{0JA}	125	°C/W
Junction to Ambient (d)(f)	R _{θJA}	111	°C/W
Junction to Ambient (d)(g)	R _{0JA}	73.5	°C/W
Junction to Ambient (e)(g)	R _{θJA}	41.7	°C/W

Notes

(a) For a dual device surface mounted on 8 sq cm single sided 2oz copper on FR4 PCB, in still air conditions with all exposed pads attached. The copper area is split down the centre line into two separate areas with one half connected to each half of the dual device.

(b) Measured at t<5 secs for a dual device surface mounted on 8 sq cm single sided 2oz copper on FR4 PCB, in still air conditions with all exposed pads attached. The copper area is split down the centre line into two separate areas with one half connected to each half of the dual device.
(c) For a dual device surface mounted on 8 sq cm single sided 2oz copper on FR4 PCB, in still air conditions with all exposed pads attached. The copper area is split down the centre line into two separate areas with one half connected to each half of the dual device.
(d) For a dual device surface mounted on 10 sq cm single sided 1oz copper on FR4 PCB, in still air conditions with all exposed pads attached attached. The copper area is split down the centre line into two separate areas with one half connected to each half of the dual device.

(e) For a dual device surface mounted on 85 sq cm single sided 20z copper on FR4 PCB, in still air conditions with all exposed pads attached attached. The copper area is split down the centre line into two separate areas with one half connected to each half of the dual device. (f) For a dual device with one active die.

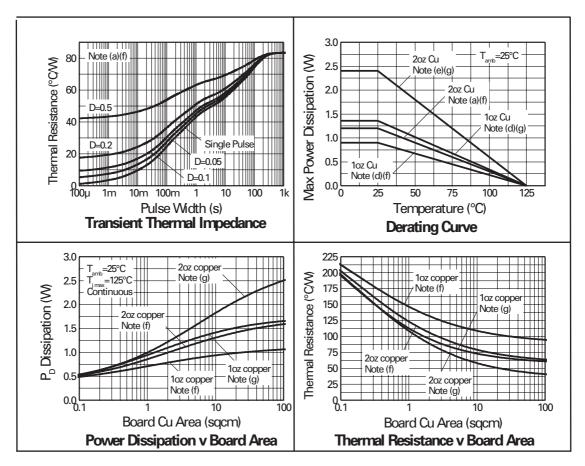
(g) For dual device with 2 active die running at equal power.

(h) Repetitive rating - pulse width limited by max junction temperature. Refer to Transient Thermal Impedance graph.

(i) The minimum copper dimensions required for mounting are no smaller than the exposed metal pads on the base of the device as shown in the package dimensions data. The thermal resistance for a dual device mounted on 1.5mm thick FR4 board using minimum copper 1 oz weight, 1mm wide tracks and one half of the device active is Rth = 250°C/W giving a power rating of Ptot = 400mW.









ISSUE 1 - JUNE 2002

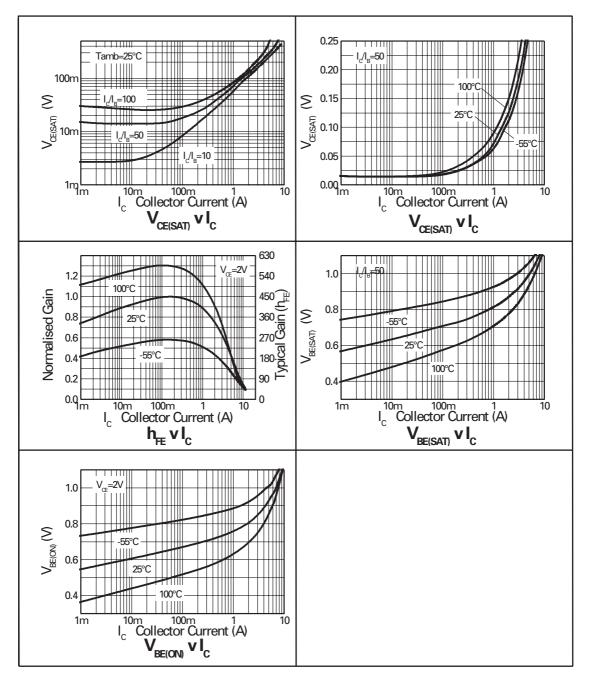
ELECTRICAL CHARACTERISTICS (at T_{amb} = 25°C unless otherwise stated).

PARAMETER	SYMBOL	MIN.	TYP.	MAX.	UNIT	CONDITIONS.	
TRANSISTOR ELECTRICAL CHARA	CTERISTICS					1	
Collector-Base Breakdown Voltage	V _{(BR)CBO}	40	100		V	I _C =100μA	
Collector-Emitter Breakdown Voltage	V _{(BR)CEO}	20	27		V	I _C =10mA*	
Emitter-Base Breakdown Voltage	V _{(BR)EBO}	7.5	8.2		V	I _E =100μA	
Collector Cut-Off Current	I _{CBO}			25	nA	V _{CB} =32V	
Emitter Cut-Off Current	I _{EBO}			25	nA	V _{EB} =6V	
Collector Emitter Cut-Off Current	I _{CES}			25	nA	V _{CES} =16V	
Collector-Emitter Saturation Voltage	V _{CE(sat)}		8 90 115 190 210	15 150 135 250 270	mV mV mV mV mV	$\begin{array}{l} I_{C}{=}0.1A, I_{B}{=}10mA^{*} \\ I_{C}{=}1A, I_{B}{=}10mA^{*} \\ I_{C}{=}2A, I_{B}{=}50mA^{*} \\ I_{C}{=}3A, I_{B}{=}100mA^{*} \\ I_{C}{=}4.5A, I_{B}{=}125mA^{*} \end{array}$	
Base-Emitter Saturation Voltage	V _{BE(sat)}		0.98	-1.05	V	I _C =4.5A, I _B =125mA*	
Base-Emitter Turn-On Voltage	V _{BE(on)}		0.88	-0.95	V	I _C =4.5A, V _{CE} =2V*	
Static Forward Current Transfer Ratio	h _{FE}	200 300 200 100	400 450 360 180				
Transition Frequency	f _T	100	140		MHz	I _C =50mA, V _{CE} =10V f=100MHz	
Output Capacitance	C _{obo}		23	30	pF	V _{CB} =10V, f=1MHz	
Turn-On Time	t _(on)		170		ns	V _{CC} =10V, I _C =3A	
Turn-Off Time	t _(off)		400		ns	I _{B1} =I _{B2} =10mA	
SCHOTTKY DIODE ELECTRICAL CH	IARACTERIS	TICS					
Reverse Breakdown Voltage	V _{(BR)R}	40	60		V	I _R =300μA	
Forward Voltage	V _F		240 265 305 355 390 425 495 420	270 290 340 400 450 500 600 	mV mV mV mV mV mV	I _F =50mA* I _F =100mA* I _F =250mA* I _F =500mA* I _F =750mA* I _F =1000mA* I _F =1500mA* I _F =1000mA,T _a =100°C*	
Reverse Current	I _R		50	100	μA	V _R =30V	
Diode Capacitance	C _D		25		pF	f=1MHz,V _R =25V	
Reverse Recovery Time	t _{rr}		12		ns	switched from $I_F = 500$ mA to $I_R = 500$ m. Measured at $I_R = 50$ mA	

*Measured under pulsed conditions.



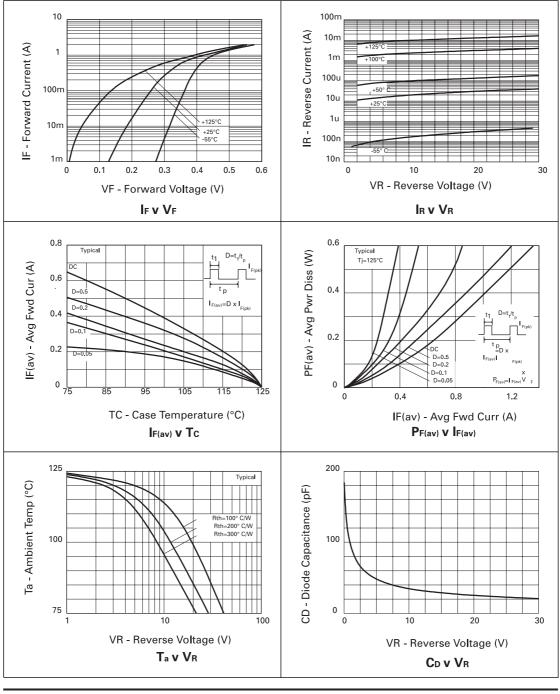




7

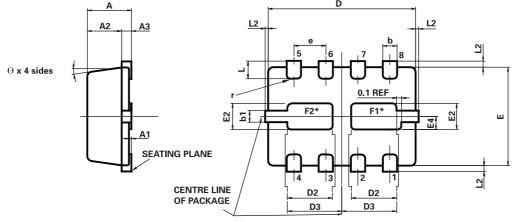


SCHOTTKY TYPICAL CHARACTERISTICS



ZETEX

ISSUE 1 - JUNE 2002



MLP832 PACKAGE OUTLINE (3mm x 2mm Micro Leaded Package)

*Exposed Flags. Solder connection to improve thermal dissipation is optional. F1 at collector 1 potential F2 at collector 2 potential

CONTROLLING DIMENSIONS IN MILLIMETRES APPROX. CONVERTED DIMENSIONS IN INCHES

MLP832 PACKAGE DIMENSIONS

	MILLIN	IETRES	INC	HES			MILLIN	IETRES	INC	HES
DIM	MIN.	MAX.	MIN.	MAX.	DIM	MIN.	MAX.	MIN.	MAX.	
Α	0.80	1.00	0.031	0.039	е	0.65	REF	0.025	6 BSC	
A1	0.00	0.05	0.00	0.002	E	2.00	BSC	0.0787	7 BSC	
A2	0.65	0.75	0.0255	0.0295	E2	0.43	0.63	0.017	0.0249	
A3	0.15	0.25	0.006	0.0098	E4	0.16	0.36	0.006	0.014	
b	0.24	0.34	0.009	0.013	L	0.20	0.45	0.0078	0.0157	
b1	0.17	0.30	0.0066	0.0118	L2		0.125	0.00	0.005	
D	3.00	BSC	0.118	BSC	r 0.075 BSC		0.0029 BSC			
D2	0.82	1.02	0.032	0.040	θ	0 °	12°	0°	12°	
D3	1.01	1.21	0.0397	0.0476						

© Zetex plc 2002

Europe		Americas	Asia Pacific
Zetex plc	Zetex GmbH	Zetex Inc	Zetex (Asia) Ltd
Fields New Road	Streitfeldstraße 19	700 Veterans Memorial Hwy	3701-04 Metroplaza, Tower 1
Chadderton	D-81673 München	Hauppauge, NY11788	Hing Fong Road
Oldham, OL9 8NP			Kwai Fong
United Kingdom	Germany	USA	Hong Kong
Telephone (44) 161 622 4422	Telefon: (49) 89 45 49 49 0	Telephone: (631) 360 2222	Telephone: (852) 26100 611
Fax: (44) 161 622 4420	Fax: (49) 89 45 49 49 49	Fax: (631) 360 8222	Fax: (852) 24250 494
uksales@zetex.com	europe.sales@zetex.com	usa.sales@zetex.com	asia.sales@zetex.com

These offices are supported by agents and distributors in major countries world-wide.

This publication is issued to provide outline information only which (unless agreed by the Company in writing) may not be used, applied or reproduced for any purpose or form part of any order or contract or be regarded as a representation relating to the products or services concerned. The Company reserves the right to alter without notice the specification, design, price or conditions of supply of any product or service.

For the latest product information, log on to www.zetex.com

ISSUE 1 - JUNE 2002

